

ABSTRACT

The present invention provides a monolithic ceramic electronic component of which the insulation resistance is hardly reduced in a high-temperature loading test and which has high reliability and a method for manufacturing the monolithic ceramic electronic component. The monolithic ceramic electronic component includes external electrodes each including a sintered electrode layer, an intermediate electroplated layer, and a plated layer, these layers being arranged in that order.

The monolithic ceramic electronic component includes a first external electrode 5, a second external electrode 6, and a ceramic sintered compact 4 including internal electrodes 2 and 3, the first and second external electrodes 5 and 6 being disposed on both end faces 4a and 4b of the ceramic sintered compact 4. The first and second external electrodes 5 and 6 have a multilayer structure in which sintered electrode layers 5a and 6a, intermediate electroplated layers 5b and 6b, and plated layers 5c and 6c are arranged in that order. Exposed surface regions 7a of insulating oxides 7 are exposed from the outer faces of the sintered electrode layers 5a and 6a, the oxides 7 being derived from a glass frit contained in the sintered electrode layers. Metals 8 are deposited on the exposed surface regions 7a and the intermediate electroplated layers

5b and 6b are then formed by electroplating.